

Rigaku X-ray Analytical Instrumentation Presented at 35th International Geological Congress

Rigaku is promoting its diverse lines of X-ray diffraction (XRD) and X-ray fluorescence (XRF) instrumentation at the 35th International Geological Congress (IGC)

August 27, 2016 – Cape Town, South Africa. [Rigaku Corporation](#), a global leader in X-ray analytical instrumentation, is being represented by [Wirsam Scientific](#) at the [35th International Geological Congress](#) conference to showcase its latest X-ray analytical technology. The South African event is taking place at the Cape Town International Convention Centre, running from 27 August to 4 September 2016. The International Geological Congress is the premier event of the International Union of Geological Sciences ([IUGS](#)).

X-ray analysis techniques are routinely employed in geological research and have become more powerful with small spot excitation, mapping, and standardless quantitative analysis. X-ray fluorescence (XRF) is the key technique for characterizing the element composition of geological materials, while X-ray diffraction (XRD) is employed to quantitatively measure phase composition. Rigaku technology and expertise provide a number of unique solutions for these types of analysis, which are being presented at booth C3.

Among the instruments on display at the event is the [Rigaku NEX QC+](#) energy dispersive X-ray fluorescence (EDXRF) analyzer. The NEX QC+ is a compact elemental analyzer that delivers rapid quantitative determination of sodium ($_{11}\text{Na}$) to uranium ($_{92}\text{U}$) in solids, liquids, powders and alloys. Specifically designed for routine quality control applications, the new NEX QC+ features an intuitive “icon-driven” touchscreen interface and built-in printer for easy operation and convenience. The 50 kV X-ray tube and Peltier cooled silicon drift detector (SDD) deliver outstanding repeatability and long-term reproducibility with excellent element peak resolution.



**Rigaku NEX QC+ Energy Dispersive X-ray
Fluorescence Spectrometer**

Also being presented is the fifth generation [Rigaku MiniFlex](#) benchtop X-ray diffraction (XRD) instrument. The MiniFlex is a general purpose X-ray diffractometer that can perform qualitative and quantitative analysis of polycrystalline materials. Ideally suited for today's fast-paced XRD analyses, the MiniFlex delivers speed and sensitivity through innovative technology enhancements, such as the optional D/teX high speed detector coupled with the new higher power X-ray source and a state of the art graphite monochromator paired with a standard scintillation counter to maximize sensitivity by optimizing signal-to-noise ratios.

More information about the MiniFlex benchtop X-ray diffractometer is available at www.myminiflex.com.

Information about geological and mineralogical analysis solutions from Rigaku is available at <http://www.rigaku.com/industry/geology>.



**Rigaku MiniFlex Benchtop
X-ray diffraction (XRD)
Spectrometer**

About Rigaku

Since its inception in Japan in 1951, Rigaku has been at the forefront of analytical and industrial instrumentation technology. Rigaku and its subsidiaries form a global group focused on general-purpose analytical instrumentation and the life sciences. With hundreds of major innovations to their credit, Rigaku companies are world leaders in X-ray spectrometry, diffraction, and optics, as well as small molecule and protein crystallography and semiconductor metrology. Today, Rigaku employs over 1,400 people in the manufacturing and support of its analytical equipment, which is used in more than 90 countries around the world supporting research, development, and quality assurance activities. Throughout the world, Rigaku continuously promotes partnerships, dialog, and innovation within the global scientific and industrial communities.

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